

**Search Notes**

Application/Control No.

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Examiner

Edgardo San Martin

Applicant(s)/Patent under  
Reexamination

CHOI ET AL.

Art Unit

2837

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference text search; see printout		7/5/2006	ESM

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
All of the previous searches were updated	7/5/2006	ESM